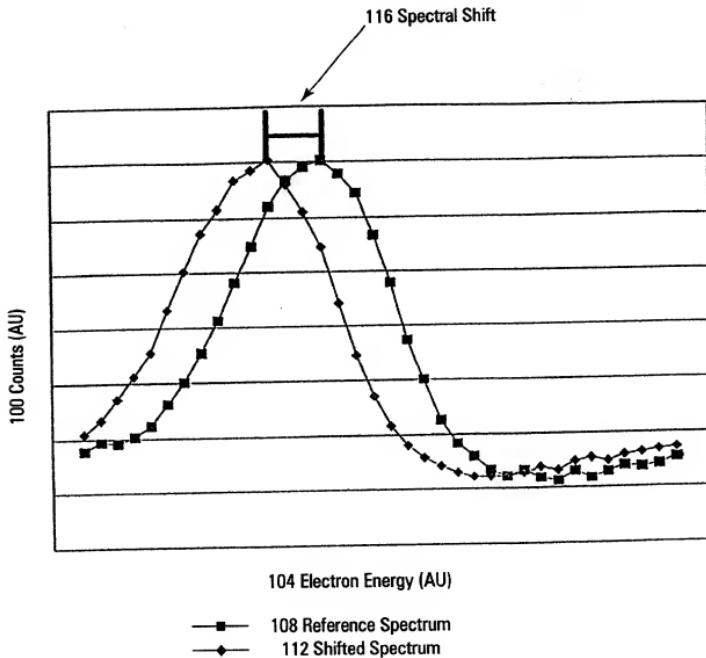


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*Fig. 1*  
*(Prior Art)*

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Spectra for Depth Profile of Charging  $\text{SiO}_2$  on Si  
(Si KLL Auger Spectra)

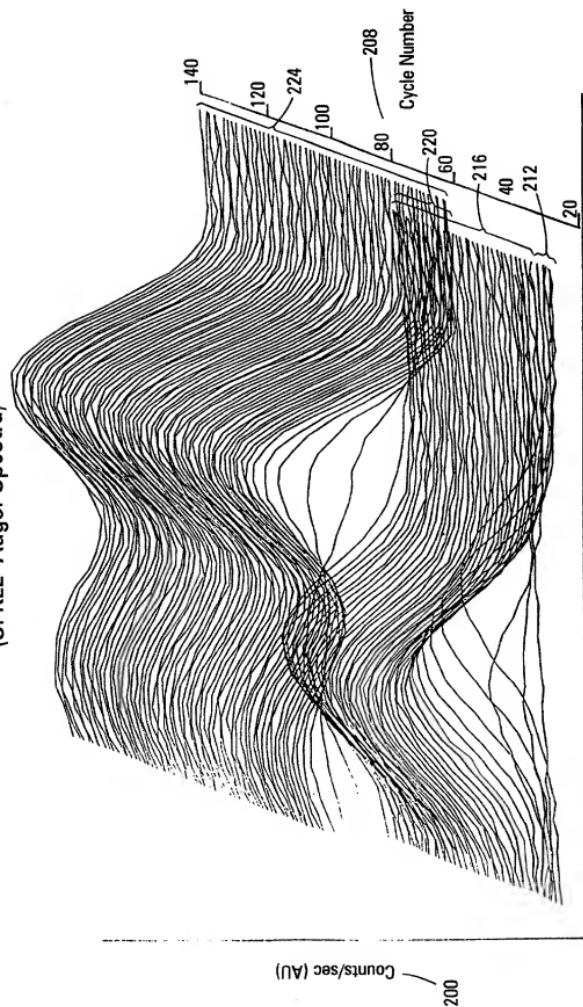


Fig. 2  
(Prior Art)

202050 " 9EBZ GBT  
Profiles of Scaled Target-Factor Weighting Factors from Factor Analysis  
of Uncompensated Auger Spectra from Charging SiO<sub>2</sub> on Si Substrate

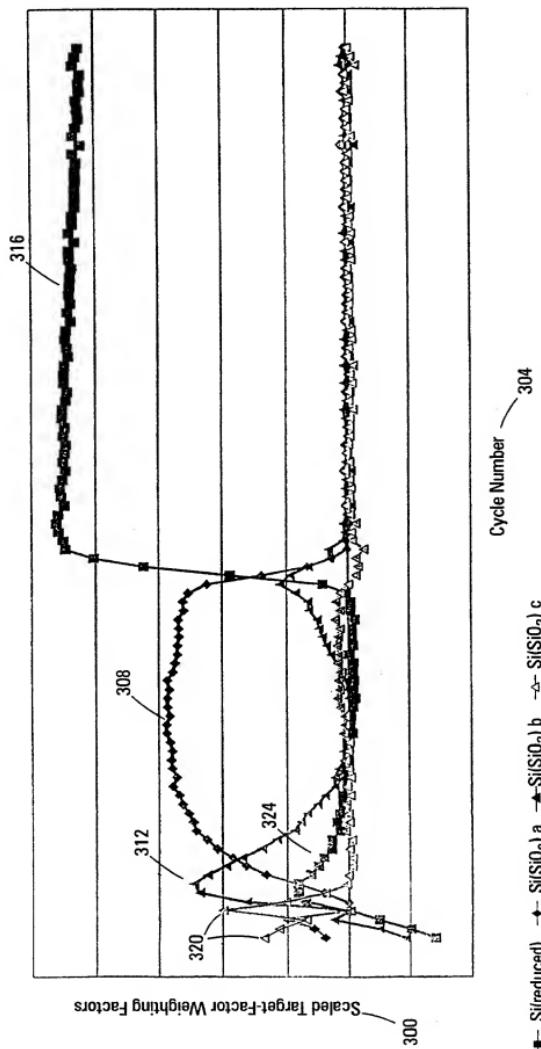


Fig. 3  
(Prior Art)

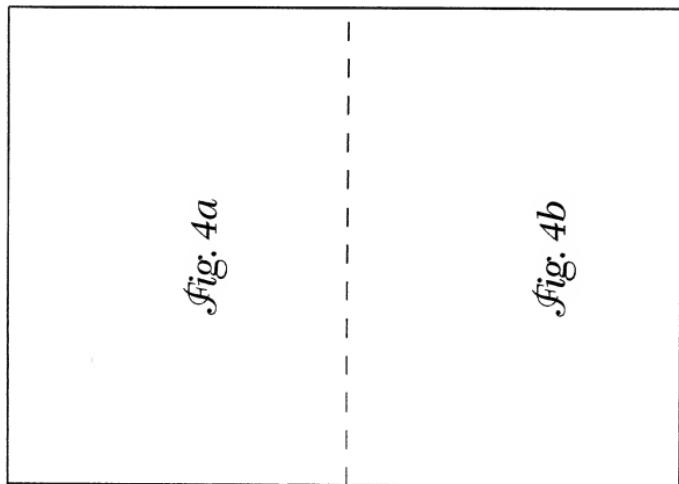
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202050 " SEC 42 GGT

*Fig. 4*

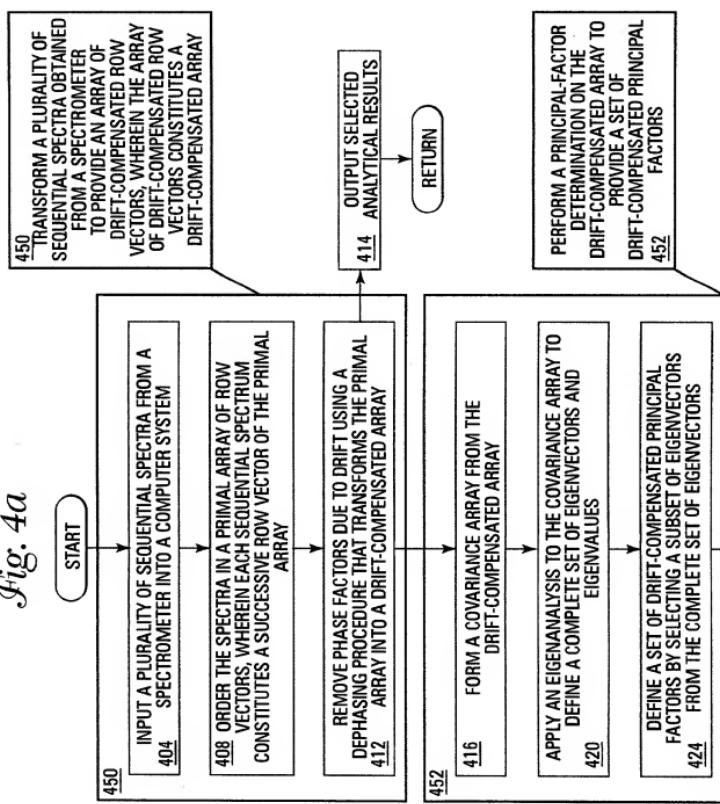


400

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Fig. 4a



202055 " SEC2Z001T

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202350" SEC. 4 037"

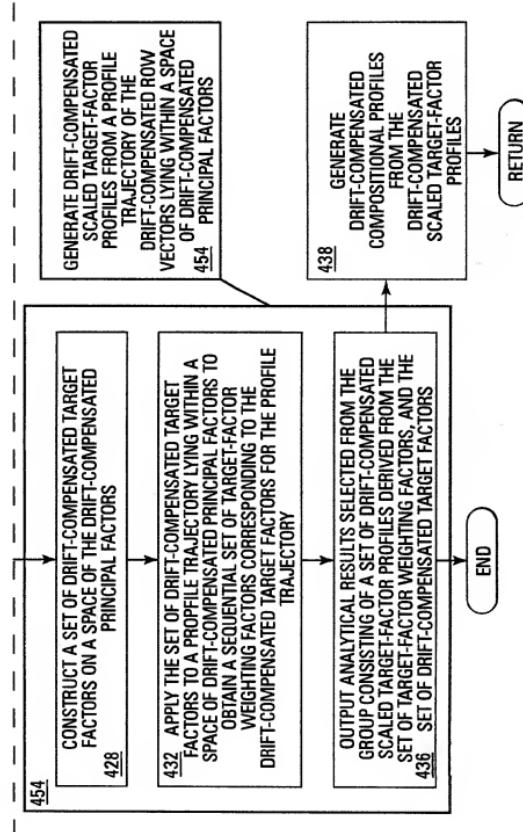


Fig. 4b

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SEARCHED = SEARCHED  
INDEXED = INDEXED  
FILED = FILED

Moduli of Fourier-transformed Spectra  
for Depth Profile of Charging  $\text{SiO}_2$  on Si

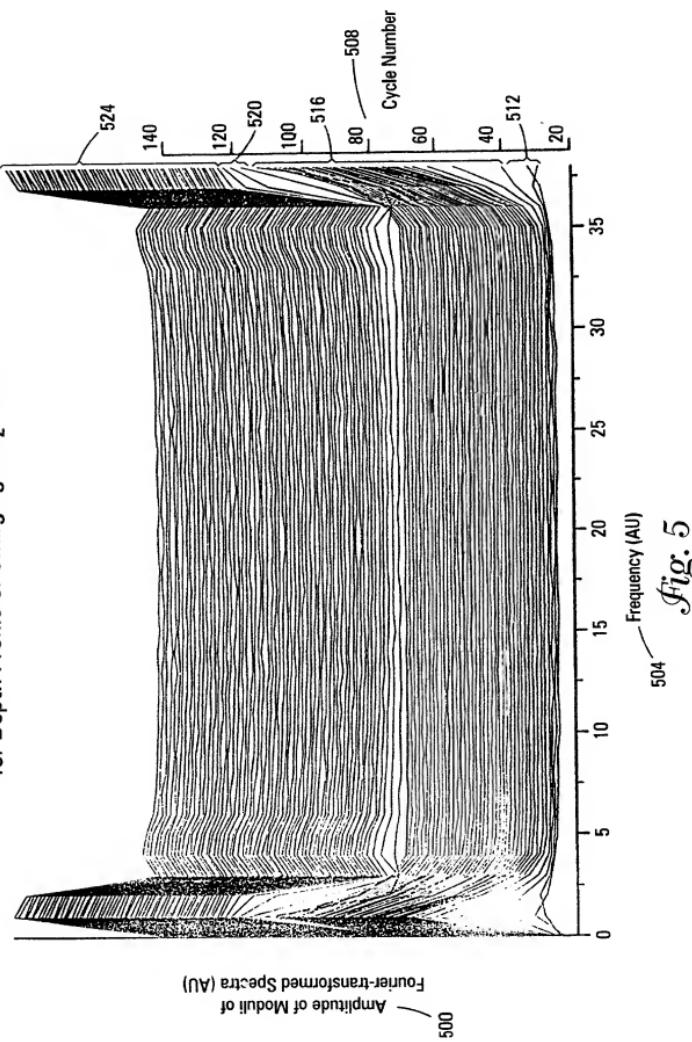


Fig. 5

202350 " 3 E02Z DDT

Profiles of Scaled Target-Factor Weighting Factors from Factor Analysis of Moduli  
of Fast-Fourier-Transformed Auger Spectra from Charging SiO<sub>2</sub> on Si Substrate

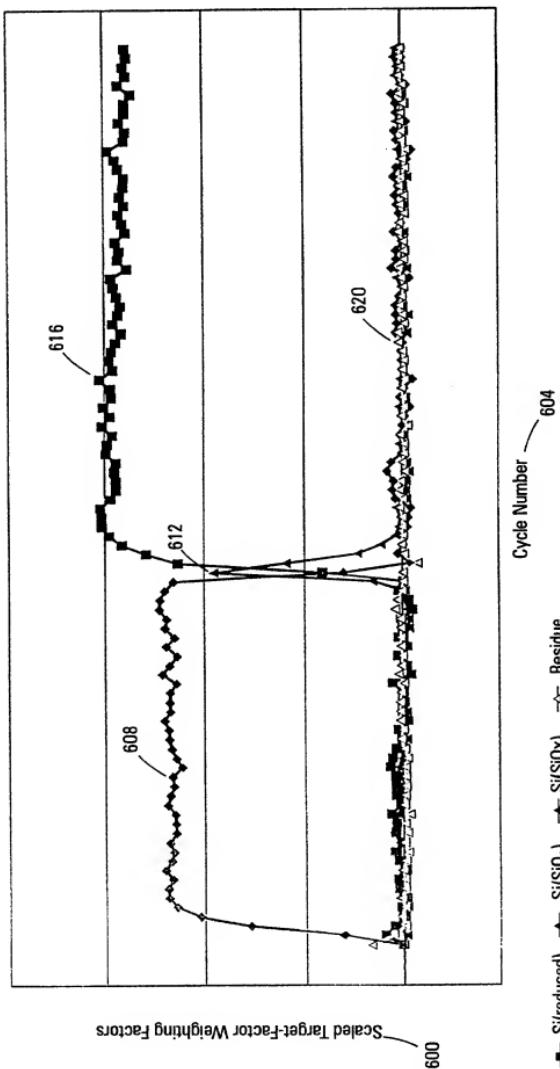


Fig. 6

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2020550 " 9502243937

Drift-Compensated Spectra Synthesized  
from Selected Reference Spectra Fit to Primal Spectra  
for Depth Profile of Charging  $\text{SiO}_2$  on Si

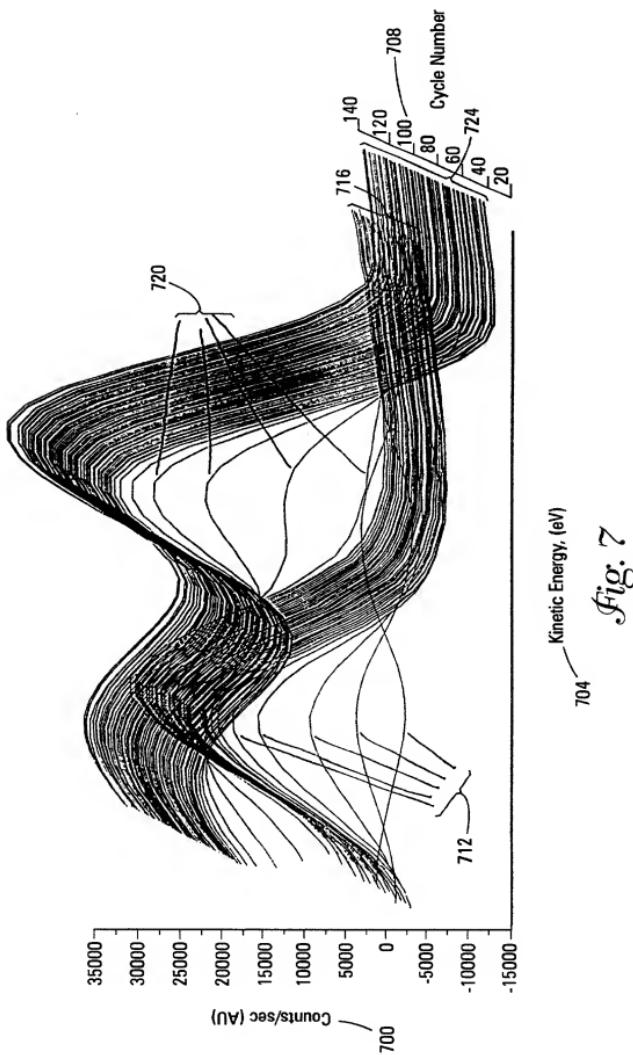
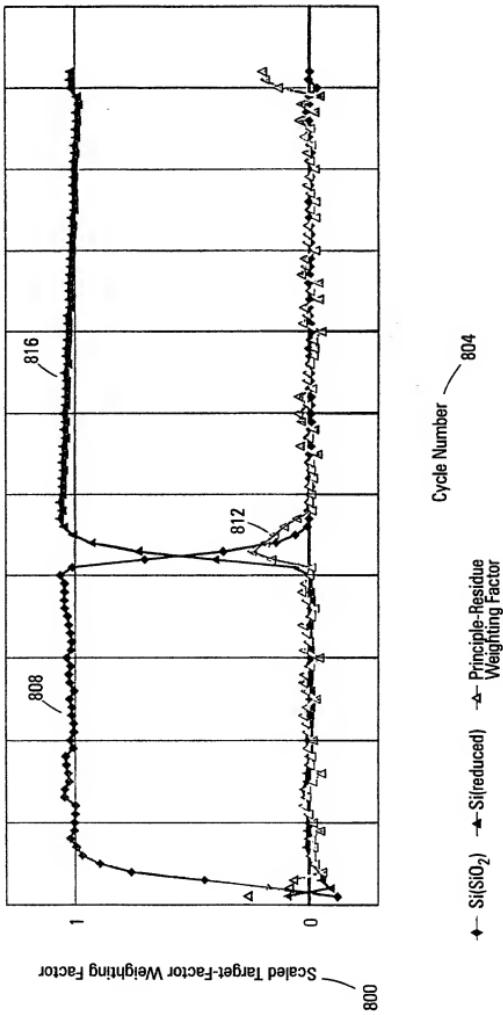


Fig. 7

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202050" SECZ230V

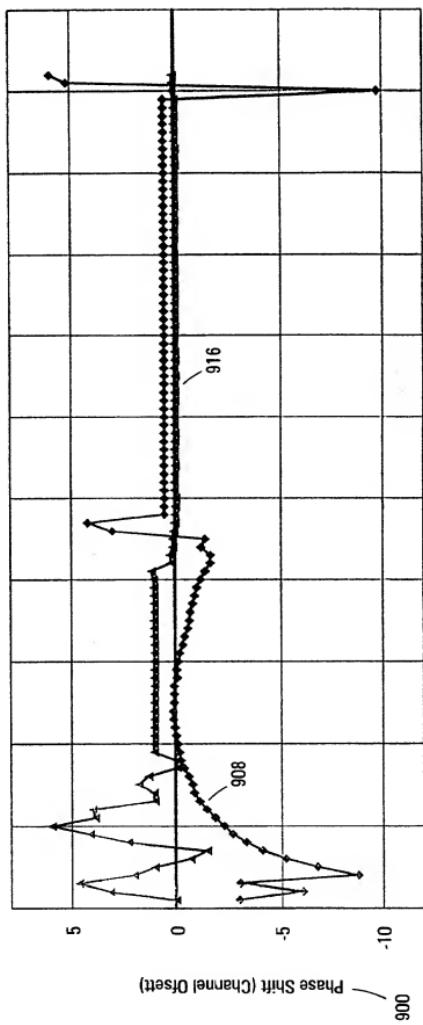
Profiles of Scaled Target-Factor Weighting Factors from Nonlinear-  
 Least-Squares Fitting of Selected Reference Spectra to Primal Spectra and  
 Profile of Principle Residue Weighting Factor from Eigenanalysis of Residues



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202000" SEC'D ZONE  
Profiles of Phase Factors for Selected Reference  
Spectra Obtained from Fitting to Primal Spectra

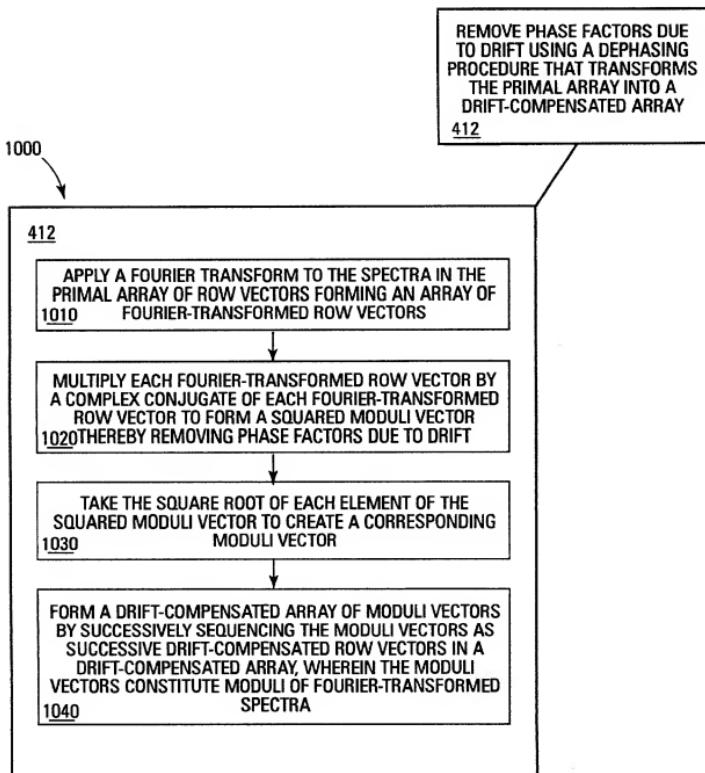


Cycle Number  
Fig: 9  
904  
♦ Si(SiO<sub>2</sub>) → Si(reduced)

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20020505 \* 05020505 \* 05020505 \* 05020505



*Fig. 10*

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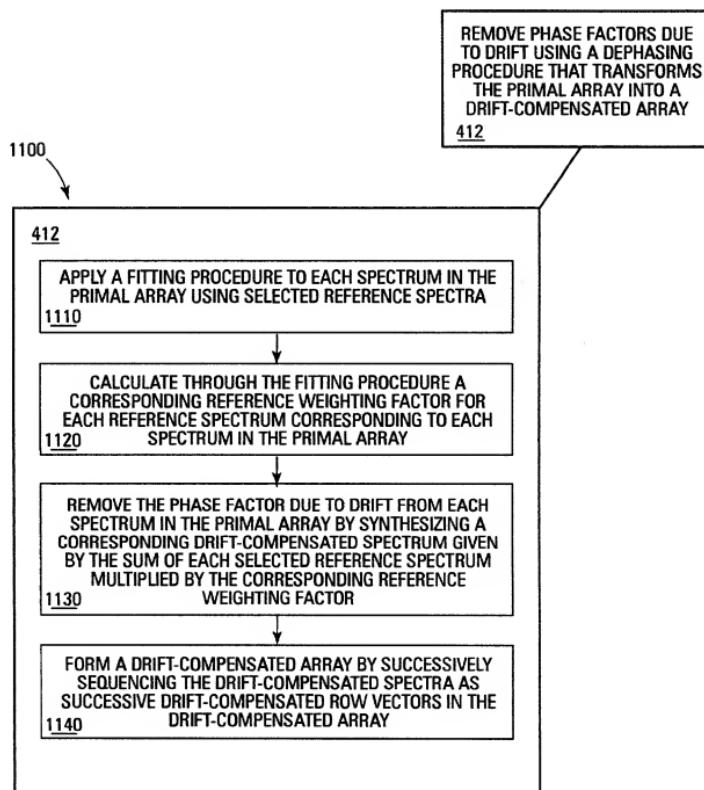


Fig. 11

METHOD FOR REMOVING THE EFFECTS OF CHARGING FROM AUGER ELECTRON SPECTROSCOPY  
AND ESCA COMPOSITION DEPTH PROFILES  
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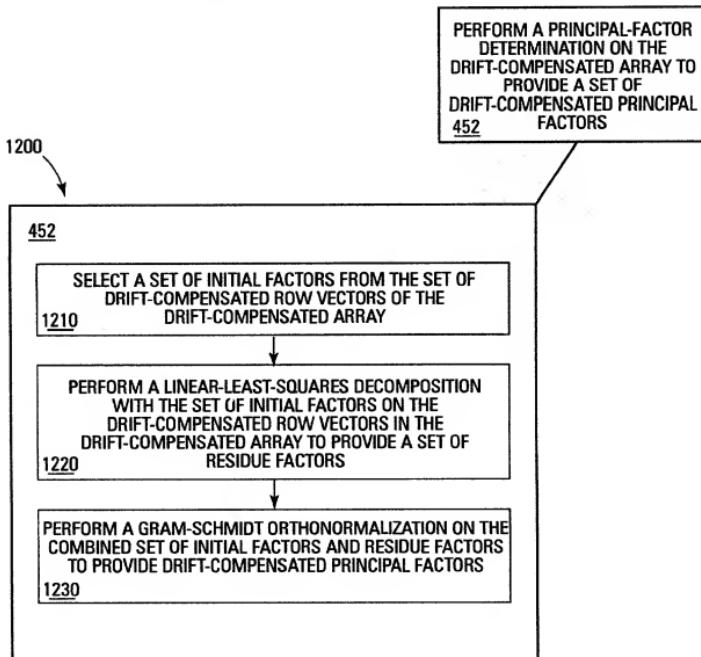
1200  
1210  
1220  
1230  
452  
453

Fig. 12

METHOD FOR REMOVING THE EFFECTS OF CHARGING FROM AUGER ELECTRON SPECTROSCOPY  
AND ESCA COMPOSITION DEPTH PROFILES  
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SEARCH-SEQ/200T

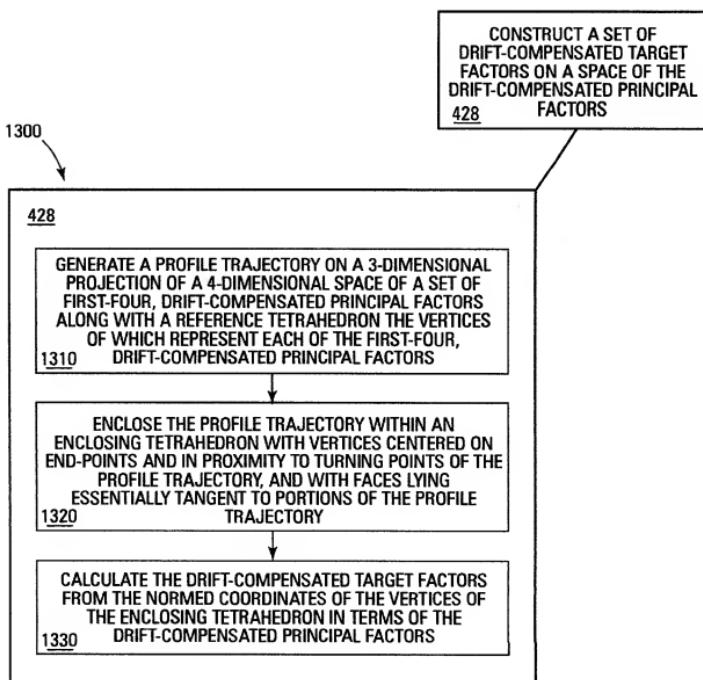
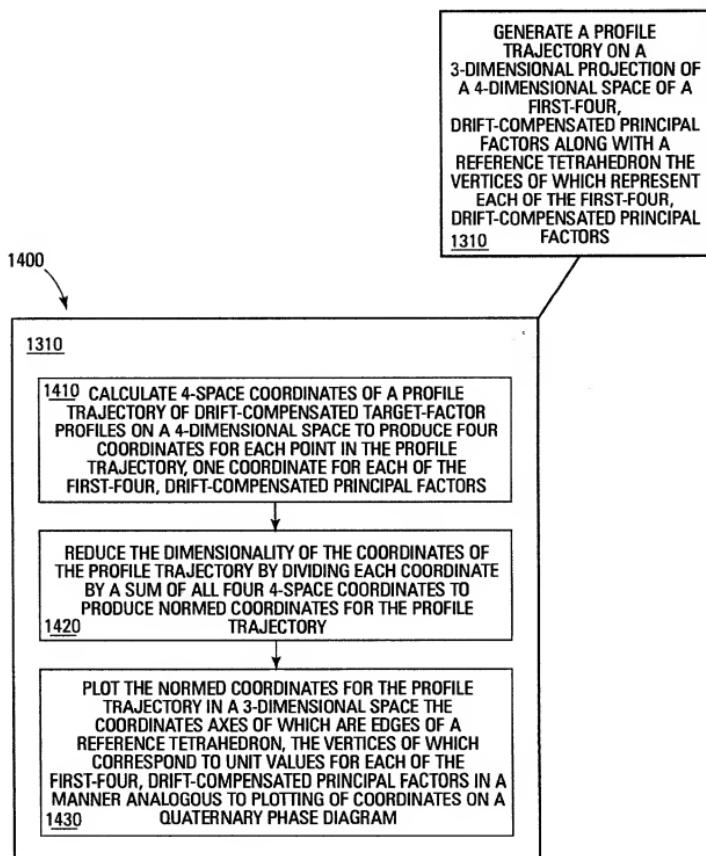


Fig. 13

METHOD FOR REMOVING THE EFFECTS OF CHARGING FROM AUGER ELECTRON SPECTROSCOPY  
AND ESCA COMPOSITION DEPTH PROFILES  
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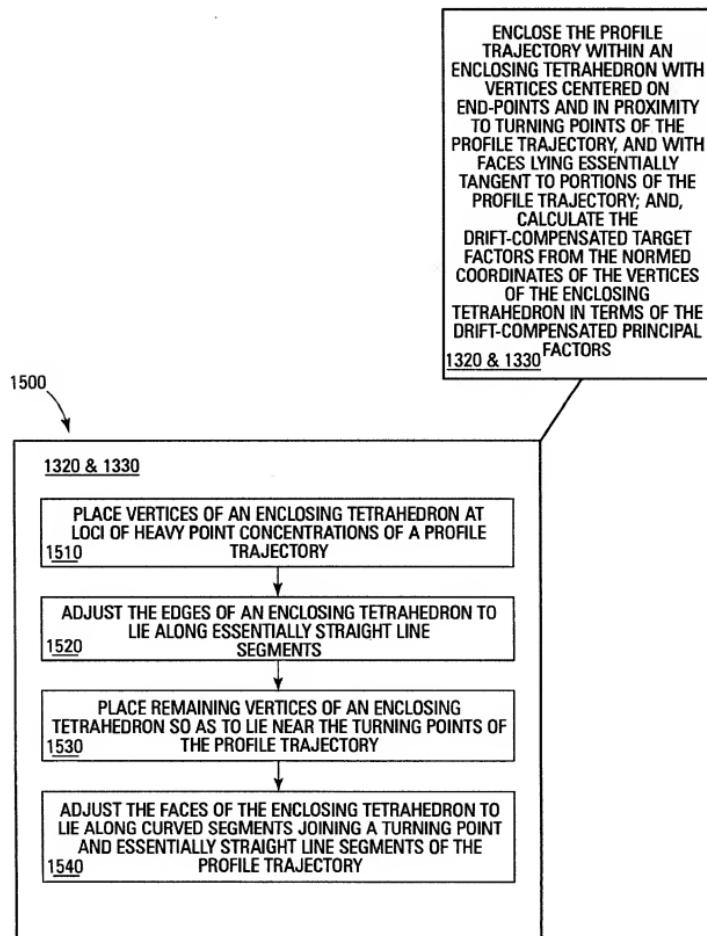
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*Fig. 14*

METHOD FOR REMOVING THE EFFECTS OF CHARGING FROM AUGER ELECTRON SPECTROSCOPY  
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SEARCHED - SERIALIZED

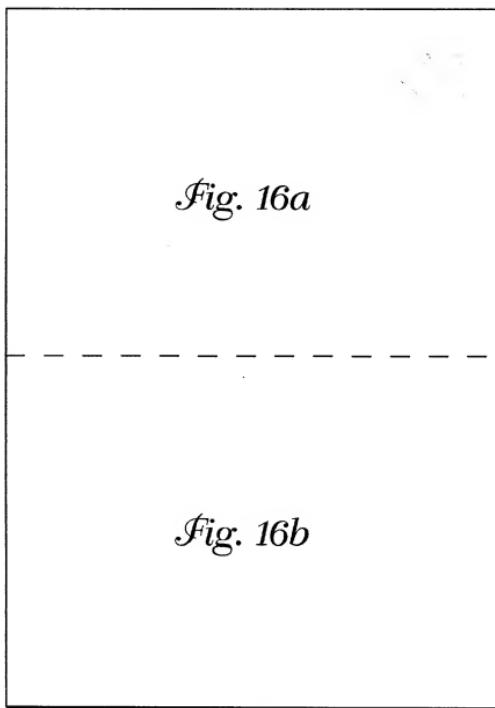
*Fig. 15*

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*Fig. 16b*

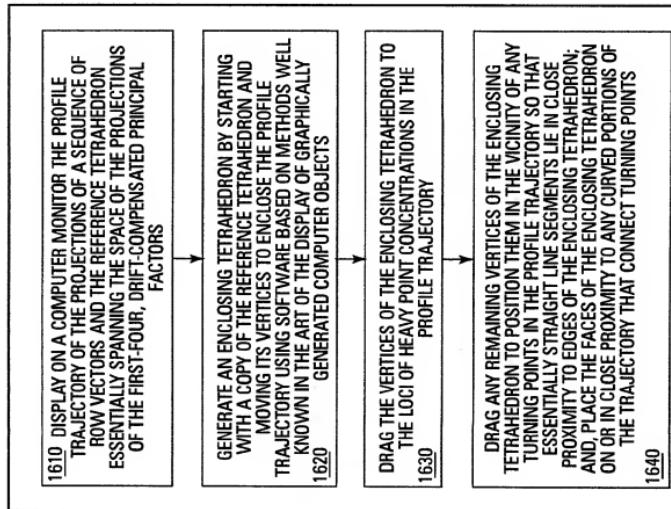
*Fig. 16*

METHOD FOR REMOVING THE EFFECTS OF CHARGING FROM AUGER ELECTRON SPECTROSCOPY  
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Fig. 16a



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202050 " SEC 29 CT

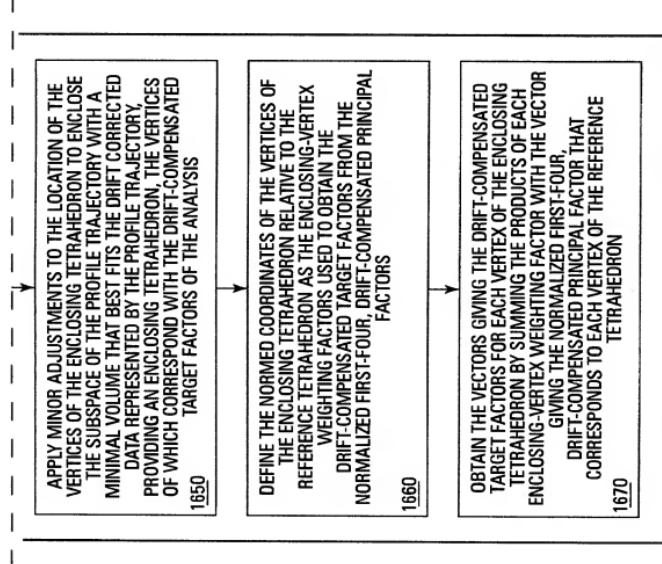
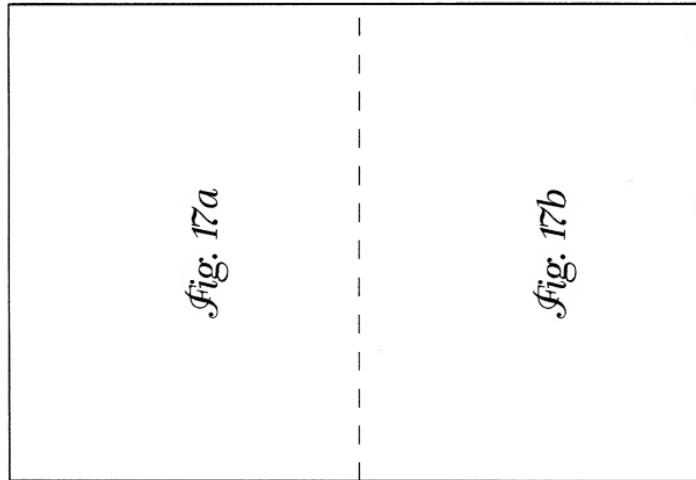


Fig. 16b

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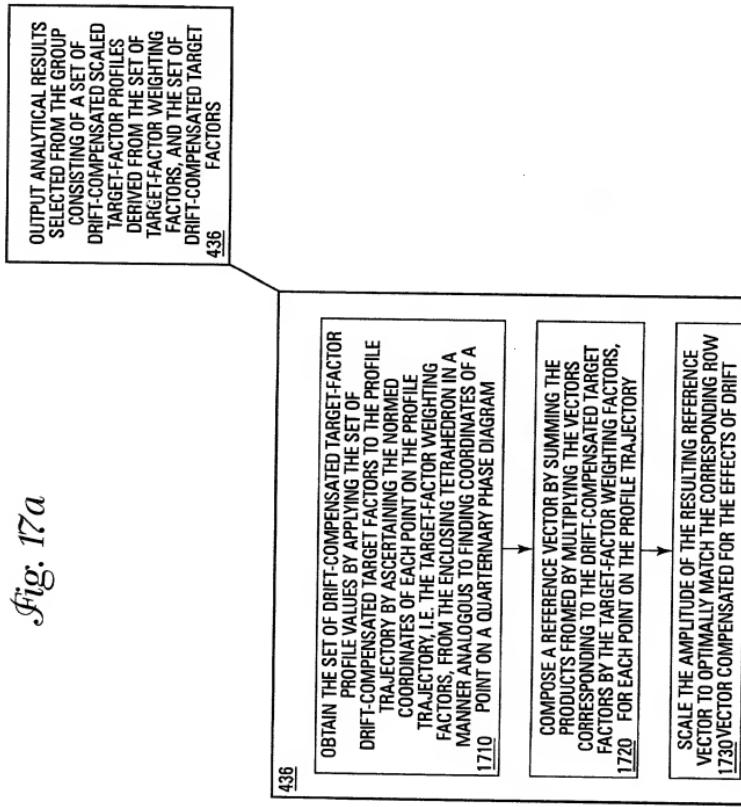
*Fig. 17*



1700

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*Fig. 17a*

202000 " 35352500

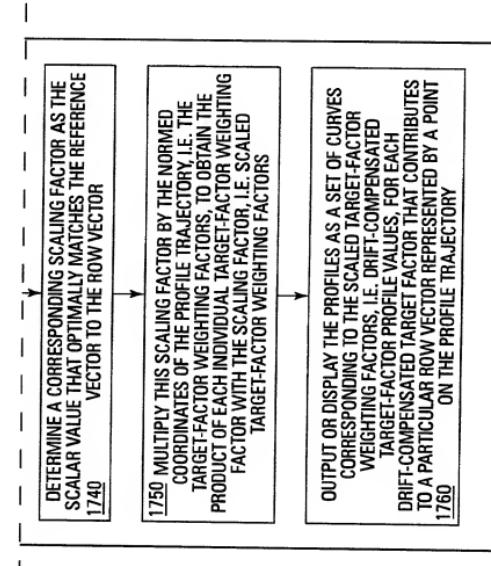
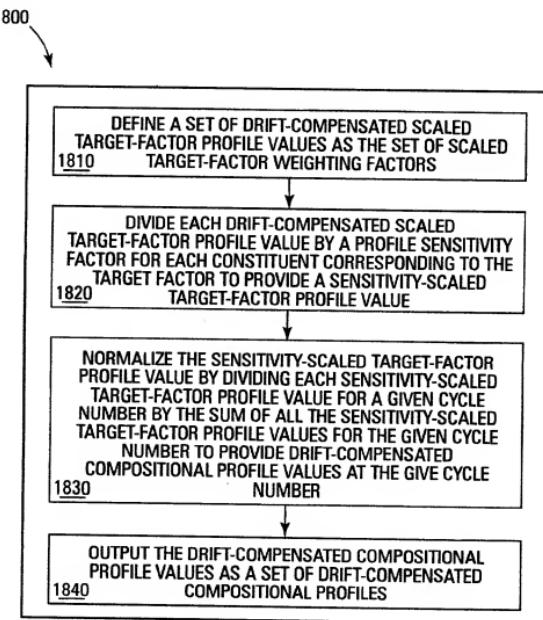


Fig. 17b

Parker et al.  
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1800  
1810  
1820  
1830  
1840



*Fig. 18*

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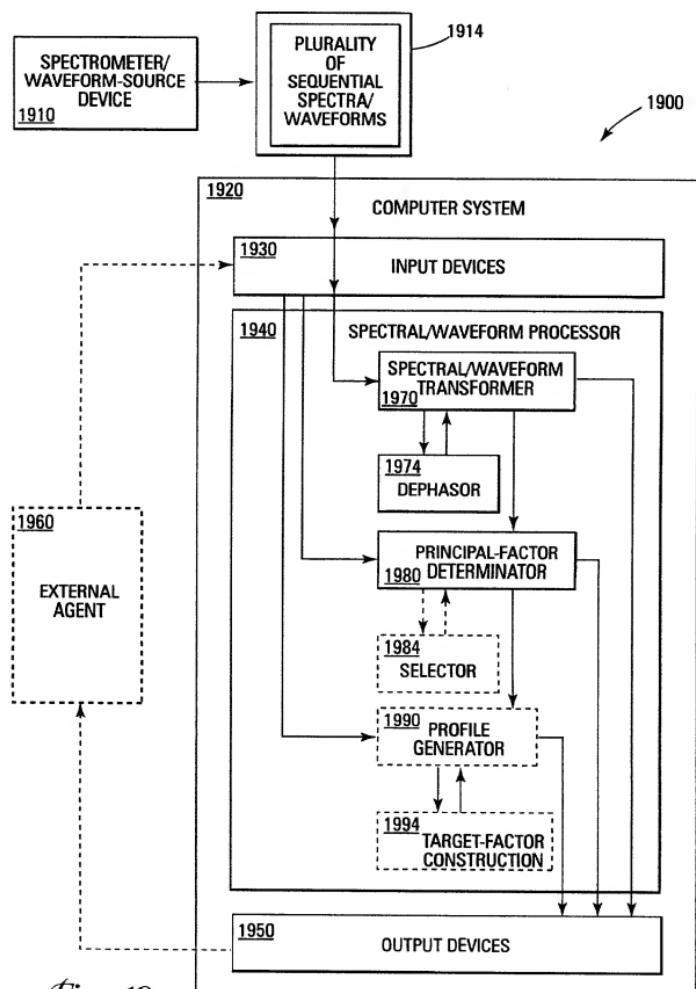


Fig. 19

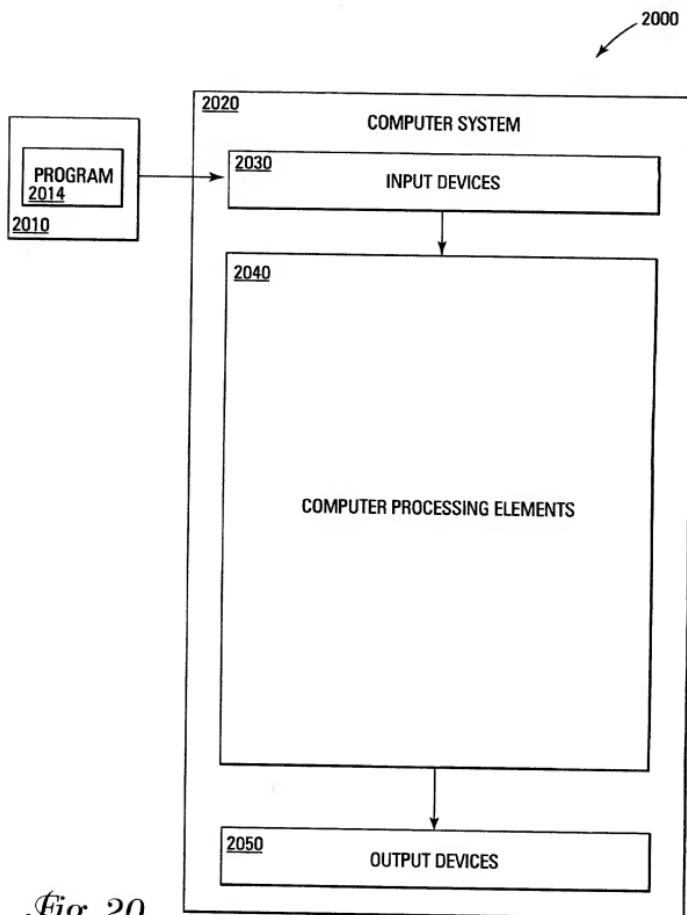


Fig. 20